

**Search Notes**

Application/Control No.

10/782,859

Examiner

Y. J. Han

Applicant(s)/Patent under  
Reexamination

YOKOYAMA ET AL.

Art Unit

2838

**SEARCHED**

Class	Subclass	Date	Examiner
323	241		
	246		
	268		
	274		
	275		
	277		
	283		
	284		
	285		
	290	6/05	JH

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
323	284		
	275		
	283	6/05	JH

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR